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N-277 FEATURES INSTRUMENTATION AMPLIFIERS

THRESHOLD 500 nano-amp. ±75 nano amps (Set by external voltage;

1 volt = 1 u amp.). Input impedance Rin is 330 ohms

POLARITY Both positive and negative inputs are provided. Each input is

protected with two diodes connected to ground.

Always ground all unused inputs in order to minimize the

input noise.

NOISE 100 hz for 16 channels: 400 hz maximum for an individual

channel

Test conditions: Threshold 0.5 volts; negative inputs shunted

by 50 ohms; positive inputs grounded.

TIME WALK 8.5 nano-sec maximum, 6.5 nano-sec, typical average.

Test conditions: Threshold 0.5 volts. Test pulses 1.3 and 6.5

micro-amps.

CROSSTALK Adjacent channels, greater than 30 db, Non adjacent channels

FAST OR Delivers -0.6 ma from a current source, i.e. -30 mv into 50

INPUT

OUTPUTS

SIGNAL Drives 16 differential ECL lines into a 34 conductor ribbon OUTPUTS

cable. 50 nano second pulse width: limits the cable length to

less than 150 feet!

TEST PULSE The test pulse applies a signal to the input of every channel.

Boards are supplied with the negative test pulses enabled. A

jumper wire selects either positive or negative test pulse

inputs

POWER 350 mw per channel. Protected against accidental power

reversal! Total power for a 16 channel card: +5 volts 0.4 amp:

-5 volts 0.68 amp.

N-277-C Positive and Negative inputs; Rin = 330 ohms.

N-277-C3 Negative inputs Rin = 330 ohms. Positive inputs grounded.

FERMILAB standard.

N277-CD Positive and Negative inputs; Rin = 56 ohms. May be used as

a silicon detector line amp/disc. With line input impedance of

N277L L indicates two power connectors, on the input and output side of the card. REPLACES LeCroy part number 2735PC.

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